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| Notice of References Cited | Application/Control No. 10/695,102 | Applicant(s)/Patent Under Reexamination BEHZAD ET AL. | |
| | Examiner Henry K. Choe | Art Unit 2817 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------------|----------------|
| | A | US-5,757,229 | 05-1998 | Mitzlaff, James Edward | 330/124R |
| | B | US-5,694,085 | 12-1997 | Walker, Mark A. | 330/295 |
| | C | US-5,438,684 | 08-1995 | Schwent et al. | 455/552.1 |
| | D | US-5,451,907 | 09-1995 | Keane et al. | 330/296 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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